



PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT 1 - PCN # : A1811-01

PCN Type: Add alternate Bump Location & Change Assembly Location & Assembly Material Sets

Data Sheet Change: N/A

Detail Of Change:

This notification is to advise our customers that IDT is adding Amkor Korea as an alternate bump location on the above products. In addition, the assembly location will also be transferred from Amkor Philippines to Amkor Korea as a result of Amkor Philippines discontinuing the assembly processes of these products.

Amkor Korea is currently a qualified IDT Subcontractor.

There is no change in form, fit and function of the products including RoHS compliance and MSL rating.

IDT requests customers to respond to this notice within 30 days, with an indication if samples will be required. Samples must be placed within 30 days if required for qualification and approval to avoid any disruption in supply.

FCCSP-48: Qualified Material Sets, by Assembly Subcontractor

	Existing	New
Die Bump Location	ATT - Amkor, Taiwan	ATT - Amkor, Taiwan and ATK - Amkor, Korea
Material Set / Assembly	ATP - Amkor, Philippines	ATK - Amkor, Korea
Die Bump	Sn1.8Ag	Sn1.8Ag
Underfill Material	MUF-1	MUF-32
Substrate	NVMUX 4L	NVMUX 4L
Solder Balls	Sn96.5/Ag3.0/Cu0.5	Sn96.5/Ag3.0/Cu0.5



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Qualification Information and Qualification Data:

Affected Packages: FCCSP-48

Assembly Material: The affected package type is using the respective subcon standard materials as shown on page 1 of this attachment. Qualification testing was completed on the worse case package.

Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests

Qualification Vehicle: FCCSP-48 (3 lots)

Test Description	Test Method	Test Results (Rej/SS)		
		Lot 1	Lot 2	Lot 3
¹ HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0 / 25	0 / 25	0 / 25
¹ HAST - unbiased (130 °C/85% RH, 96 Hrs)	JESD22-A118	0 / 25	0 / 25	0 / 25
¹ Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0 / 25	0 / 25	0 / 25
High Temperature Storage Test (150°C, 1000 hours)	JESD22-A103	0 / 25	0 / 25	0 / 25

Notes: 1. HAST and Temperature Cycle were subjected to Preconditioning per JESD22-A113 for MSL 3.